

Search Notes

Application/Control No.

10/765,370

Examiner

Hiep Nguyen

Applicant(s)/Patent under
Reexamination

MCRAE ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	108	03.03.05	Hiep
	205	-	-
	206	-	-
326	81		
	82		
	83		
	85		
	87	↓	↓

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	03.03.05	Hiep
See attachment		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner